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Machine Vision in Industrial Systems

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Deadline for manuscript submissions:

closed (15 May 2024)

Message from the Guest Editor

Our focus extends to exploring the practical applications of machine vision in industrial automation, such as product quality inspection, production process monitoring, automated warehouse management, and industrial robot navigation. Moreover, the integration of machine vision with the industrial internet, artificial intelligence, embedded systems, and other fields will be explored to promote digitalization and intelligence in industrial production.

This Special Issue invites contributions that span a wide array of topics, including, but not limited to, the following subjects:

- Artificial intelligence;
- Machine learning;
- Deep learning;
- Machine vision:
- Intelligent manufacturing and digital factory;
- Product quality inspection;
- Production process monitoring;
- Industrial robot navigation and positioning;
- Robot vision recognition technology.











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Message from the Editor-in-Chief

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